

# **CoolMOS<sup>™</sup> Power Transistor**

#### **Features**

- ullet Worldwide best  $R_{
  m ds,on}$  in TO220
- Ultra low gate charge
- Extreme dv/dt rated
- · High peak current capability
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Pb-free lead plating; RoHS compliant

## CoolMOS CS is specially designed for:

- Hard switching SMPS topologies
- Zero-voltage switching SMPS topologies
- CCM PFC

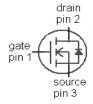
#### **Product Summary**

V <sub>DS</sub>	600	V
$R_{\mathrm{DS(on),max}}$	0.099	Ω
Q <sub>g,typ</sub>	60	nC

#### PG-TO220-3-1



Туре	Package	Ordering Code	Marking
IPP60R099CS	PG-TO220-3-1	Q67045A5018	6R099



## **Maximum ratings,** at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	31	А
		T <sub>C</sub> =100 °C	19	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	93	
Avalanche energy, single pulse	E <sub>AS</sub>	I <sub>D</sub> =11 A, V <sub>DD</sub> =50 V	800	mJ
Avalanche energy, repetitive $t_{AR}^{(2),3)}$	E <sub>AR</sub>	I <sub>D</sub> =11 A, V <sub>DD</sub> =50 V	1.2	
Avalanche current, repetitive $t_{AR}^{(2),3)}$	I <sub>AR</sub>		11	А
MOSFET dv/dt ruggedness	dv/dt	V <sub>DS</sub> =0480 V	50	V/ns
Gate source voltage	$V_{GS}$	static	±20	V
		AC (f>1 Hz)	±30	
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	255	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
Mounting torque		M3 and M3.5 screws	60	Ncm



# **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous diode forward current	Is	T <sub>C</sub> =25 °C	18	А
Diode pulse current	I <sub>S,pulse</sub>	7 <sub>C</sub> -23 C	93	

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	0.5	K/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	leaded	-	-	62	
Soldering temperature, wavesoldering	$T_{\rm sold}$	1.6 mm (0.063 in.) from case for 10 s	-	-	260	°C

## **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V <sub>GS</sub> =0 V, I <sub>D</sub> =250 μA	600	ı	ı	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 1.2 \text{ mA}$	2.1	3	3.9	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =600 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	-	-	10	μΑ
		V <sub>DS</sub> =600 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =150 °C	-	tbd	-	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =18 A, T <sub>j</sub> =25 °C	-	0.09	0.099	Ω
		V <sub>GS</sub> =10 V, I <sub>D</sub> =18 A, T <sub>j</sub> =150 °C	-	0.24	-	
Gate resistance	R <sub>G</sub>	f=1 MHz, open drain	-	1.3	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =100 V,	-	2800	-	pF
Output capacitance	C oss	f=1 MHz	-	130	-	
Effective output capacitance, energy related <sup>4)</sup>	C <sub>o(er)</sub>	V <sub>GS</sub> =0 V, V <sub>DS</sub> =0 V to 480 V	-	130	-	
Effective output capacitance, time related <sup>5)</sup>	C o(tr)		-	340	-	
Turn-on delay time	t <sub>d(on)</sub>	$V_{DD}$ =400 V, $V_{GS}$ =10 V, $I_{D}$ =18 A, $R_{G}$ =3.3 $\Omega$	-	10	-	ns
Rise time	t <sub>r</sub>		-	5	-	
Turn-off delay time	$t_{d(off)}$		-	60	-	
Fall time	$t_{f}$		-	5	-	
Gate Charge Characteristics						
Gate to source charge	Q <sub>gs</sub>		-	14	-	nC
Gate to drain charge	$Q_{gd}$	V <sub>DD</sub> =400 V, I <sub>D</sub> =18 A,	-	20	-	
Gate charge total	Qg	V <sub>GS</sub> =0 to 10 V	-	60	80	
Gate plateau voltage	V <sub>plateau</sub>		-	5.0	-	V
Reverse Diode						
Diode forward voltage	$V_{SD}$	V <sub>GS</sub> =0 V, I <sub>F</sub> =18 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time	t <sub>rr</sub>		-	450	-	ns
Reverse recovery charge	Q <sub>rr</sub>	$V_R$ =400 V, $I_F$ = $I_S$ , $di_F$ / $dt$ =100 A/ $\mu$ s	-	12	-	μC
Peak reverse recovery current	I <sub>rrm</sub>		-	70	-	Α

<sup>1)</sup> J-STD20 and JESD22

 $<sup>^{2)}</sup>$  Pulse width  $t_{\rm p}$  limited by  $T_{\rm j,max}$ 

 $<sup>^{3)}</sup>$  Repetitive avalanche causes additional power losses that can be calculated as  $P_{\rm AV}$ = $E_{\rm AR}$ \*f.

 $<sup>^{4)}</sup>$  C  $_{\rm o(er)}$  is a fixed capacitance that gives the same stored energy as C  $_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 80%  $V_{\rm DSS}$ .

 $<sup>^{5)}</sup>$  C  $_{\rm o(tr)}$  is a fixed capacitance that gives the same charging time as C  $_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 80%  $V_{\rm DSS}$ .



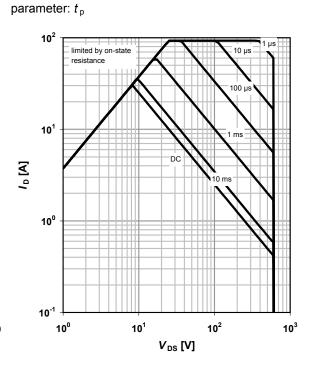
## 1 Power dissipation

$$P_{\text{tot}}$$
=f( $T_{\text{C}}$ )

# 200 200 100 0 40 80 120 160 T<sub>C</sub> [°C]

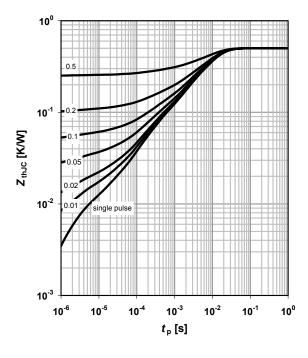
#### 2 Safe operating area

$$I_{D} = f(V_{DS}); T_{C} = 25 \text{ °C}; D = 0$$



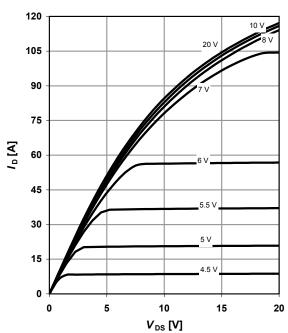
#### 3 Max. transient thermal impedance

 $I_D = f(V_{DS}); T_j = 25 \text{ °C}$ parameter:  $D = t_p / T$ 



## 4 Typ. output characteristics

 $I_{\rm D}$ =f( $V_{\rm DS}$ );  $T_{\rm j}$ =25 °C parameter:  $V_{\rm GS}$ 

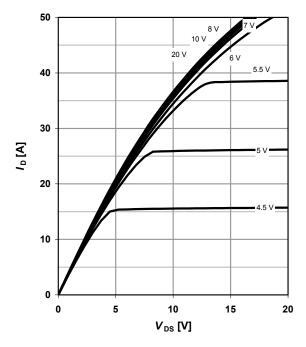




## 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 150 °C$ 

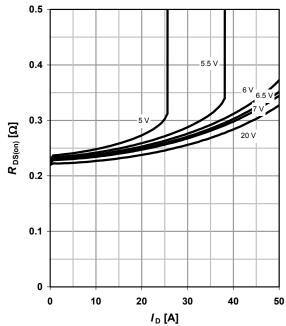
parameter:  $V_{\rm GS}$ 



#### 6 Typ. drain-source on-state resistance

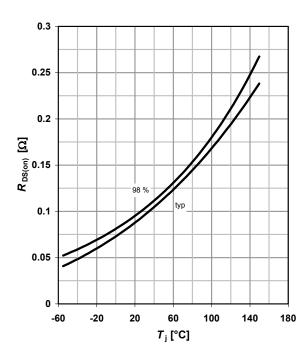
 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =150 °C

parameter:  $V_{\rm GS}$ 



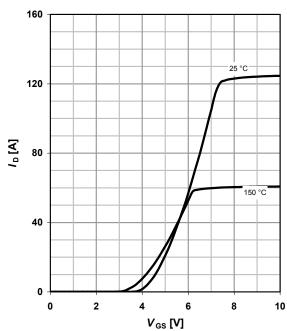
#### 7 Drain-source on-state resistance

 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =18 A;  $V_{GS}$ =10 V



## 8 Typ. transfer characteristics

 $I_{\rm D}$ =f( $V_{\rm GS}$ );  $|V_{\rm DS}|$ >2 $|I_{\rm D}|R_{\rm DS(on)max}$ parameter:  $T_{\rm j}$ 

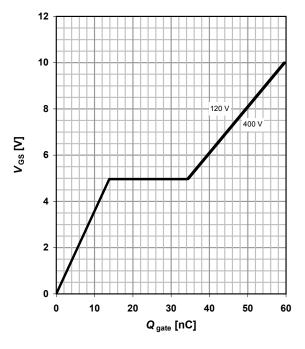




## 9 Typ. gate charge

 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =18 A pulsed

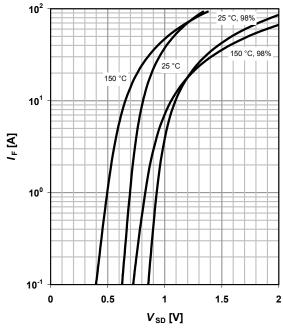
parameter: V<sub>DD</sub>



#### 10 Forward characteristics of reverse diode

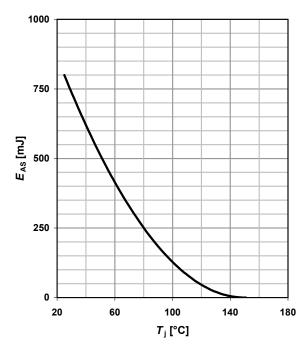
 $I_F = f(V_{SD})$ 

parameter: T<sub>j</sub>



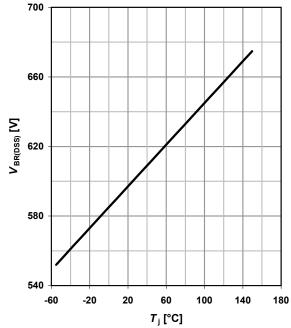
#### 11 Avalanche energy

$$E_{AS}$$
=f( $T_j$ );  $I_D$ =11 A;  $V_{DD}$ =50 V



## 12 Drain-source breakdown voltage

$$V_{BR(DSS)}$$
=f( $T_j$ );  $I_D$ =0.25 mA



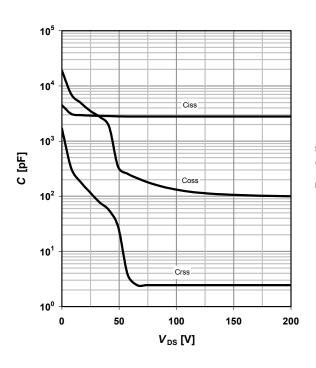


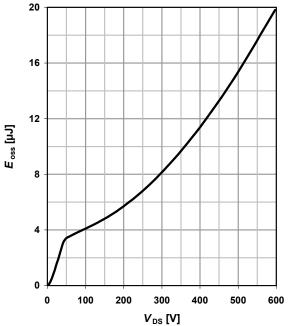
## 13 Typ. capacitances

# $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$

## 14 Typ. Coss stored energy

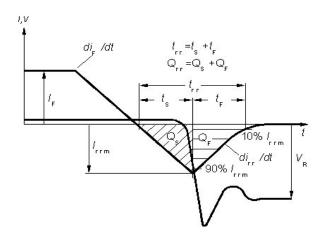
$$E_{oss} = f(V_{DS})$$

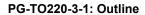


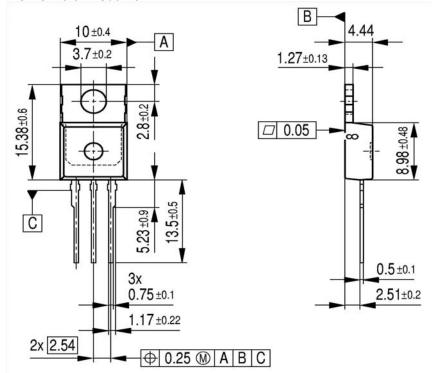




#### **Definition of diode switching characteristics**







All metal surfaces tin plated, except area of cut. Metal surface min. x=7.25, y=12.3

Dimensions in mm



Published by Infineon Technologies AG Bereich Kommunikation St.-Martin-Straße 53 D-81541 München © Infineon Technologies AG 1999 All Rights Reserved.

#### Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

#### Information

For further information on technology, delivery terms and conditions and prices, please contact your nearest Infineon Technologies office in Germany or our Infineon Technologies representatives worldwide (see address list).

#### Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact your nearest Infineon Technologies office.

Infineon Technologies' components may only be used in life-support devices or systems with the expressed written approval of Infineon Technologies if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.